

STD50N03L STD50N03L-1

N-CHANNEL 30V - 9.2mΩ - 40A - DPAK/IPAK STripFET™ III Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STD50N03L	30V	10.5m Ω	40A
STD50N03L-1	30V	10.5m Ω	40A

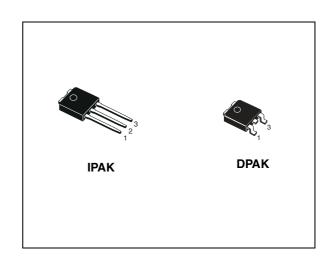
- R_{DS(on)}*Q_g industry's benchmark
- Conduction losses reduced
- Switching losses reduced
- Low threshold device

Description

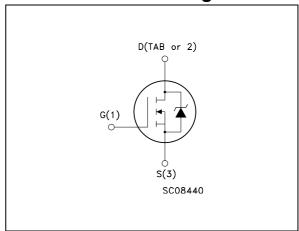
This product utilizes the latest advanced design rules of ST's proprietary STripFET™ technology. This is suitable for the most demanding DC-DC converter application where high efficiency is to be achieved.

Applications

■ Switching applications



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STD50N03L	D50N03L	DPAK	Tape & reel
STD50N03L-1	D50N03L	IPAK	Tube

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1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	30	V
V _{GS}	Gate-source voltage	±20	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25°C	40	Α
I _D	Drain current (continuous) at T _C =100°C	36	Α
I _{DM} ⁽²⁾	Drain current (pulsed)	160	Α
P _{TOT}	Total dissipation at T _C = 25°C	60	W
	Derating factor	0.4	W/°C
E _{AS} ⁽³⁾	Single pulse avalanche energy	230	mJ
T _J T _{stg}	Operating junction temperature Storage temperature	-55 to 175	°C

^{1.} Limited by wire bonding

Table 2. Thermal data

Symbol	Parameter	Value	Unit
R _{thJ-Case}	Thermal resistance junction-case max	2.5	°C/W
R _{thJ-Amb}	Thermal resistance junction-ambient max	100	°C/W
Tj	Maximum lead temperature for soldering purpose	275	°C

^{2.} Pulse width limited by safe operating area

^{3.} Starting $T_i = 25^{\circ}C$, $I_D = 20A$, $V_{DD} = 15V$

2 Electrical characteristics

(T_{CASE}=25°C unless otherwise specified)

Table 3. On/off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250\mu A, V_{GS} = 0$	30			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 30V V _{DS} = 30V, Tc=125°C			1 10	μ Α μ Α
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1			V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V, I_D = 20A$ $V_{GS} = 5V, I_D = 20A$		9.2 0.012	10.5 0.019	mΩ Ω

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} =25V, f=1MHz, V _{GS} =0		1434 294 48		pF pF pF
Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V_{DD} = 15V, I_{D} = 40A V_{GS} = 5V (see Figure 13)		10.4 5.1 3.7	14	nC nC nC
Q _{OSS} (1)	Output charge	V _{DS} = 24V ; V _{GS} =0		12.6		nC
R_{G}	Gate input resistance	f=1MHz Gate Bias Bias=0 Test signal Level=20mV open drain		1.1		Ω

^{1.} $Q_{OSS}=C_{OSS}*D V_{in}$; $C_{OSS}=C_{gd}+C_{gd}$. See *Appendix A*

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time Rise time	V_{DD} =15V, I_{D} = 25A, R_{G} = 4.7 Ω , V_{GS} = 4.5V (see Figure 12)		15 125		ns ns
t _{d(off)}	Turn-off delay time Fall time	V_{DD} = 15V, I_{D} = 25A, R_{G} = 4.7 Ω , V_{GS} = 4.5V (see Figure 12)		14 45		ns ns

Table 6. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)				40 160	A A
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} = 20A, V _{GS} =0			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 40A, di/dt = 100A/µs, V_{DD} = 10 V, Tj = 25°C (see Figure 17)		26 15.6 1.2		ns nC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I_{SD} = 40A, di/dt = 100A/µs, V_{DD} = 10V, Tj= 150°C (see Figure 17)		26.4 18.1 1.4		ns nC A

^{1.} Pulse width limited by safe operating area

^{2.} Pulsed: pulse duration=300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

Figure 2. Thermal impedance

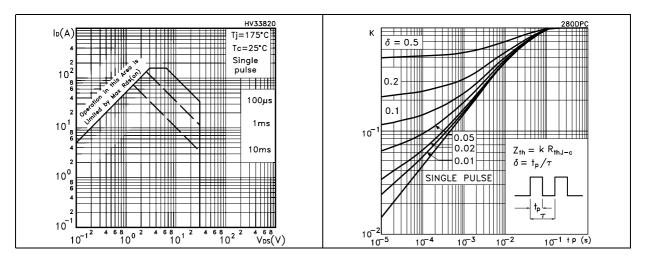


Figure 3. Output characteristics

Figure 4. Transfer characteristics

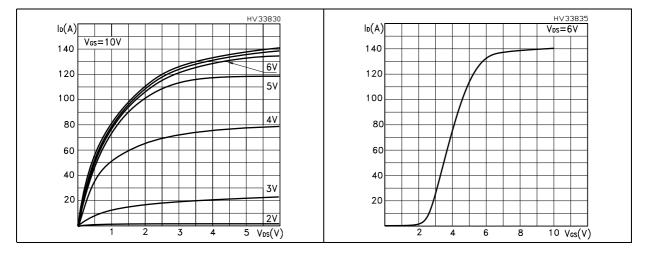
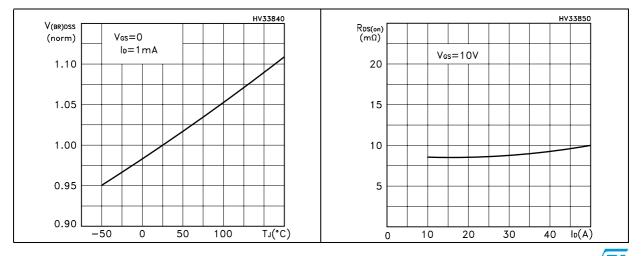


Figure 5. Normalized B_{VDSS} vs temperature Figure 6. Static drain-source on resistance



0

5

10

25 Vps(V)

HV33870 C(pF) Vgs(V) f=1MHz $V_{DD} = 15V$ V_{GS}=0V ID=50A 2000 8 1600 6 1200 800 2 400

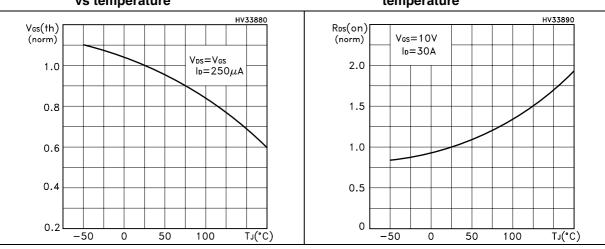
Gate charge vs gate-source voltage Figure 8. Figure 7. **Capacitance variations**

Figure 9. Normalized gate threshold voltage Figure 10. Normalized on resistance vs vs temperature

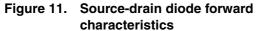
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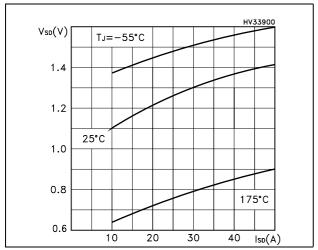
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Q_g(nC)



temperature





3 Test circuit

Figure 12. Switching times test circuit for resistive load

Figure 13. Gate charge test circuit

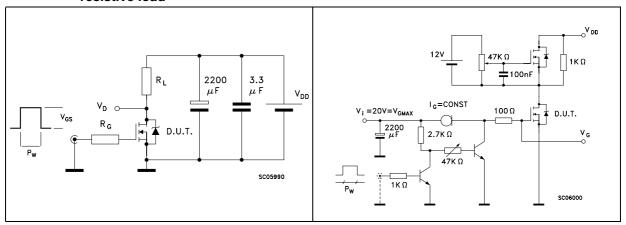


Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit

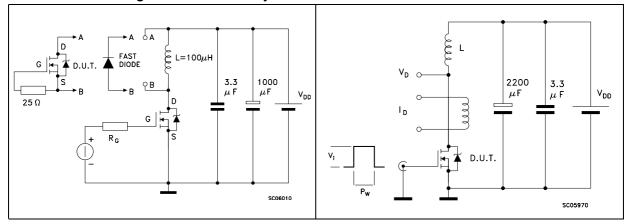
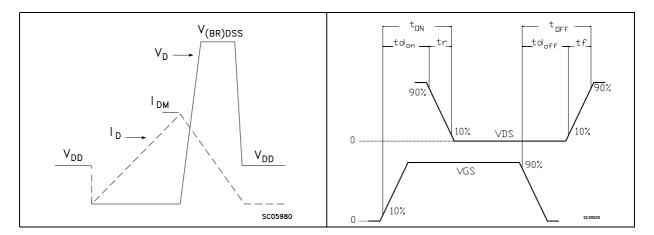


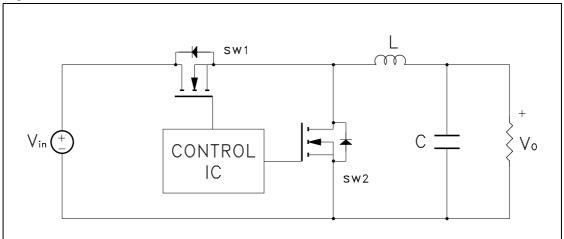
Figure 16. Unclamped inductive waveform

Figure 17. Switching time waveform



Appendix A Buck converter

Figure 18. Power losses estimation



The power losses associated with the FETs in a Synchronous Buck converter can be estimated using the equations shown in the table below. The formulas give a good approximation, for the sake of performance comparison, of how different pairs of devices affect the converter efficiency. However a very important parameter, the working temperature, is not considered. The real device behavior is really dependent on how the heat generated inside the devices is removed to allow for a safer working junction temperature.

The low side (SW2) device requires:

- Very low R_{DS(on)} to reduce conduction losses
- Small Qgls to reduce the gate charge losses
- Small Coss to reduce losses due to output capacitance
- Small Qrr to reduce losses on SW1 during its turn-on
- The Cgd/Cgs ratio lower than Vth/Vgg ratio especially with low drain to source
- voltage to avoid the cross conduction phenomenon;

The high side (SW1) device requires:

- Small Rg and Ls to allow higher gate current peak and to limit the voltage feedback on the gate
- Small Qg to have a faster commutation and to reduce gate charge losses

Low R_{DS(on)} to reduce the conduction losses.

Table 7. Power losses

		High side switching (SW1)	Low side switch (SW2)
P _{conduction}		$R_{DS(on)SW1} * I_L^2 * \delta$	$R_{DS(on)SW2} * I_L^2 * (1 - \delta)$
P _{switching}		$V_{\text{in}} * (Q_{\text{gsth(SW1)}} + Q_{\text{gd(SW1)}}) * f * \frac{I_L}{I_g}$	Zero Voltage Switching
P _{diode}	Recovery (1)	Not applicable	$V_{in} * Q_{rr(SW2)} * f$
diode	Conduction	Not applicable	$V_{f(SW2)} * I_L * t_{deadtime} * f$
$P_{gate}(Q_G)$		$Q_{g(SW1)}*V_{gg}*f$	$Q_{gls(SW2)}*V_{gg}*f$
P_{Qoss}		$\frac{V_{in} *Q_{oss(SW1)} *f}{2}$	$\frac{V_{in} *Q_{oss(SW2)} *f}{2}$

^{1.} Dissipated by SW1 during turn-on

Table 8. Paramiters meaning

Parameter	Meaning
d	Duty-cycle
Q _{gsth}	Post threshold gate charge
Q_{gls}	Third quadrant gate charge
P _{conduction}	On state losses
P _{switching}	On-off transition losses
P _{diode}	Conduction and reverse recovery diode losses
P _{gate}	Gate drive losses
P _{Qoss}	Output capacitance losses

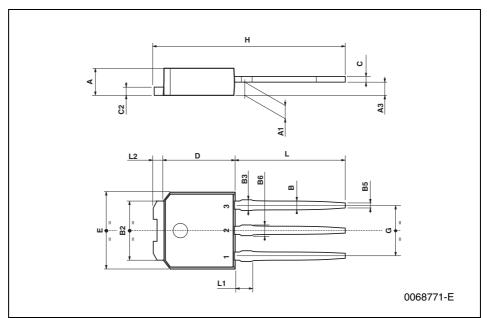
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

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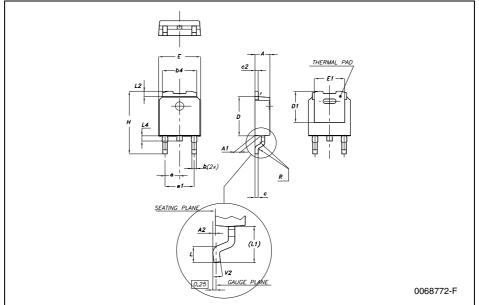
TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIW.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A3	0.7		1.3	0.027		0.051
В	0.64		0.9	0.025		0.031
B2	5.2		5.4	0.204		0.212
В3			0.85			0.033
B5		0.3			0.012	
B6			0.95			0.037
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
E	6.4		6.6	0.252		0.260
G	4.4		4.6	0.173		0.181
Н	15.9		16.3	0.626		0.641
L	9		9.4	0.354		0.370
L1	0.8		1.2	0.031		0.047
L2		0.8	1		0.031	0.039



DPAK MECHANICAL DATA

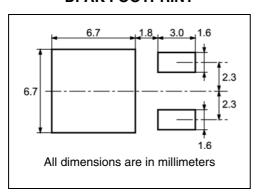
DIM.	mm.			inch		
	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	2.2		2.4	0.086		0.094
A1	0.9		1.1	0.035		0.043
A2	0.03		0.23	0.001		0.009
В	0.64		0.9	0.025		0.035
b4	5.2		5.4	0.204		0.212
С	0.45		0.6	0.017		0.023
C2	0.48		0.6	0.019		0.023
D	6		6.2	0.236		0.244
D1		5.1			0.200	
E	6.4		6.6	0.252		0.260
E1		4.7			0.185	
е		2.28			0.090	
e1	4.4		4.6	0.173		0.181
Н	9.35		10.1	0.368		0.397
L	1			0.039		
(L1)		2.8			0.110	
L2		0.8			0.031	
L4	0.6		1	0.023		0.039
R		0.2			0.008	
V2	0°		8°	0°		8°



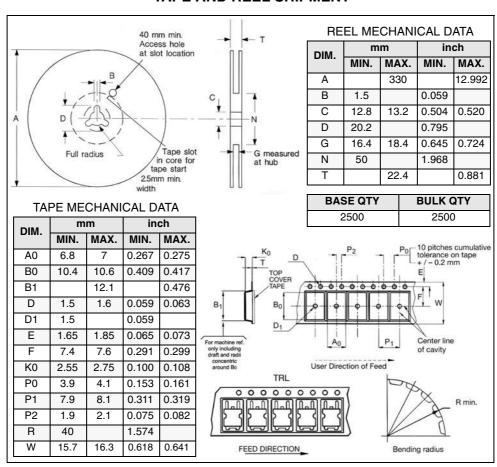
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5 Packaging mechanical data

DPAK FOOTPRINT



TAPE AND REEL SHIPMENT



6 Revision history

Table 9. Revision history

Date	Revision	Changes	
31-Jul-2006	1	Initial release.	
27-Oct-2006	2	Modified Figure 1.: Safe operating area on page 6	

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